Bounds on Reliable Boolean Function Computation with Noisy Gates

- R. L. Dobrushin & S. I. Ortyukov, 1977

- N. Pippenger, 1985
- P. Gács & A. Gál, 1994

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Oct. 5, 2011

Question

Given a network of noisy logic gates, what is the redundancy required if we want to compute the a Boolean function reliably?

- **noisy:** gates produce the wrong output independently with error probability no more than ε .
- **reliably:** the value computed by the entire circuit is correct with probability at least 1δ
- redundancy:

minimum #gates needed for reliable computation in noisy circuit minimum #gates needed for reliable computation in noiseless circuit

- noisy/noiseless complexity
- may depend on the function of interest
- upper bound: achievability
- Iower bound: converse

Part I

Lower Bounds for the Complexity of Reliable Boolean Circuits with Noisy Gates

History of development

- [Dobrushin & Ortyukov 1977]
 - Contains all the key ideas
 - Proofs for a few lemmas are incorrect
- [Pippenger & Stamoulis & Tsitsiklis 1990]
 - Pointed out the errors in [DO1977]
 - Provide proofs for the case of computing the parity function
- [Gács & Gál 1994]
 - Follow the ideas in [DO1977] and provide correct proofs
 - Also prove some stronger results

In this talk

We will mainly follow the presentation in [Gács & Gál 1994].

Problem formulation System Model

Boolean circuit C

- a directed acycic graph
- node ~ gate
- edge \sim in/out of a gate

Gate g

- a function $g: \{0,1\}^{n_g} \to \{0,1\}$
 - n_g: fan-in of the gate

Basis Φ

- a set of possible gate functions
- e.g., $\Phi = \{AND, OR, XOR\}$
- complete basis
- for circuit $C: \Phi_C$
- **maximum fan-in in** C: $n(\Phi_C)$

Assumptions

- each gate g has constant number of fan-ins ng.
- If can be represented by compositions of gate functions in ⊕_C.

Problem formulation Error models (ε, p)

Gate error

- A gate fails if its output value for $\mathbf{z} \in \{0, 1\}^{n_g}$ is different from $g(\mathbf{z})$
- gates fail independently with
 - fixed probability ε
 - used for lower bound proof
 - probability at most ε
- $\bullet \ \varepsilon \in (0, 1/2)$

Circuit error

- *C*(**x**): random variable for output of circuit *C* on input **x**.
- A circuit computes *f* with error probability at most *p* if

 $\mathbb{P}\left[C(\mathbf{x}) \neq f(\mathbf{x})\right] \le p$

for any input $\mathbf{x}.$

Problem formulation Sensitivity of a Boolean function

Let $f : \{0,1\}^n \to \{0,1\}$ be a Boolean function with binary input vector $\mathbf{x} = (x_1, x_2, \dots, x_n)$.

Let \mathbf{x}^{l} be a binary vector that differs from \mathbf{x} only in the *l*-th bit, i.e.,

$$\mathbf{x}_i^l = \begin{cases} x_i & i \neq l \\ \neg x_i & i = l \end{cases}.$$

- *f* is sensitive to the *l*th bit on \mathbf{x} if $f(\mathbf{x}^l) \neq f(\mathbf{x})$.
- Sensitivity of f on x: #bits in x that f is sensitive to.
 - "effecitive" input size
- Sensitivity of *f*: maximum over all **x**.

Asymptotic notations

•
$$f(n) = O(g(n))$$
:

$$\lim_{n \to \infty} \sup_{n \to \infty} \left| \frac{f(n)}{g(n)} \right| < \infty,$$
• $f(n) = \Omega(g(n))$:

$$\lim_{n \to \infty} \inf_{n \to \infty} \left| \frac{f(n)}{g(n)} \right| \ge 1,$$

 ${\scriptstyle \blacksquare} f(n) = \Theta \left(g(n) \right):$

$$f(n) = O(g(n))$$

and
$$f(n) = \Omega(g(n))$$

Main results

Theorem: number of gates for reliable computation

- ▶ Let ε and p be any constants such that $\varepsilon \in (0, 1/2), p \in (0, 1/2)$.
- ► Let *f* be any Boolean function with sensitivity *s*.

Under the error model (ε, p) , the number of gates of the curcuit is $\Omega(s \log s)$.

Corollary: redundancy of noisy computation

For any Boolean function of *n* variables and with O(n) noiseless complexity and $\Omega(n)$ sensitivity, the redundancy of noisy computation is $\Omega(\log n)$.

• e.g., nonconstant symmetric function of n variables has redundancy $\Omega(\log n)$

Equivalence result for wire failures

Lemma 3.1 in Dobrushin&Ortyukov

- Let $\varepsilon \in (0, 1/2)$ and $\delta \in [0, \varepsilon/n(\Phi_C)]$.
- Let y and t be the vector that a gate receives when the wire fail and does not fail respectively.

For any gate g in the circuit C there exists unique values $\eta_g(\mathbf{y},\delta)$ such that if

- the wires of C fails independently with error probability δ , and
- ► the gate g fails with probability $\eta_g(\mathbf{y}, \delta)$ when receiving input \mathbf{y} ,

then the probability that the output of g is different from $g(\mathbf{t})$ is equal to $\varepsilon.$

Insights

- Independent gate failures can be "simulated" by independently wire failures and corresponding gate failures.
- These two failure modes are equivalent in the sense that the circuit C computes f with the same error probability.

"Noisy-wires" version of the main result

Theorem

- ▶ Let ε and p be any constants such that $\varepsilon \in (0, 1/2), p \in (0, 1/2)$.
- ▶ Let *f* be any Boolean function with sensitivity *s*.

Let C be a circuit such that

- its wires fail independently with fixed probability δ , and
- each gate fails independently with probability $\eta_g(\mathbf{y}, \delta)$ when receiving \mathbf{y} .

Suppose C computes f with error probability at most p. Then the number of gates of the curcuit is $\Omega(s \log s)$.

Error analysis

Function and circuit inputs

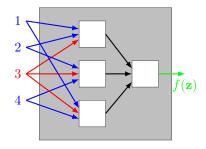
Maximal sensitive set \boldsymbol{S} for \boldsymbol{f}

- s > 0: sensitivity of f
- z: an input vector with s bits that f is sensitive to
 - an input vector where f has maximum sensitivity
- S: the set of sensitive bits in z
 - key object

B_l : edges originated from l-th input

- $\blacksquare m_l \triangleq |B_l|$
- e.g.
 - ► l = 3
 - $\triangleright B_l$

▶ $m_l = 3$



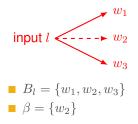
Error analysis Wire failures

For $\beta \subset B_l$, let $H(\beta)$ be the event that for wires in B_l , only those in β fail.

Let

$$\beta_l \triangleq \operatorname*{arg\,max}_{\beta \subset B_l} \mathbb{P}\left[C(\mathbf{z}^l) = f(\mathbf{z}^l) \,\middle|\, H(\beta)\right]$$

► the best failing set for input \mathbf{z}^l ■ Let $H_l \triangleq H(B_l \setminus \beta_l)$



Fact 1

$$\mathbb{P}\left[C(\mathbf{z}) \neq f(\mathbf{z}) \mid H_l\right] = \mathbb{P}\left[C(\mathbf{z}^l) = f(\mathbf{z}^l) \mid H(\beta_l)\right]$$

Proof

- f is sensitive to z_l
- $\neg z_l \Leftrightarrow$ "flip" all wires in B_l
- $\$ β_l is the worst non-failing set for input \mathbf{z}

Error analysis Error probability given wire failures

Fact 2

$$\mathbb{P}\left[C(\mathbf{z}^{l}) = f(\mathbf{z}^{l}) \,|\, H(\beta_{l})\right] \ge 1 - p$$

Proof

$$\blacktriangleright \mathbb{P}\left[C(\mathbf{z}^l) = f(\mathbf{z}^l)\right] \ge 1 - p$$

 $\models \ \beta_l \text{ maximizes } \mathbb{P}\left[C(\mathbf{z}^l) = f(\mathbf{z}^l) \, \middle| \, H(\beta)\right]$

Fact 1 & 2 \Rightarrow Fact 3 For each $l \in S$,

$$\mathbb{P}\left[C(\mathbf{z}) \neq f(\mathbf{z}) \mid H_l\right] \ge 1 - p$$

where $\{H_l, l \in S\}$ are independent events. Furthermore, Lemma 4.3 in [Gács&Gál 1994] shows

$$\mathbb{P}\left[C(\mathbf{z}) \neq f(\mathbf{z}) \middle| \bigcup_{l \in S} H_l\right] \ge (1 - \sqrt{p})^2$$

• The error probability given H_l or $\bigcup_{l \in S} H_l$ is relatively large.

Error analysis Bounds on wire failure probabilities Note

$$p \ge \mathbb{P}\left[C(\mathbf{z}) \neq f(\mathbf{z})\right]$$
$$\ge \mathbb{P}\left[C(\mathbf{z}) \neq f(\mathbf{z}) \middle| \bigcup_{l \in S} H_l\right] \mathbb{P}\left[\bigcup_{l \in S} H_l\right]$$

Fact 3 implies

Fact 4

$$\mathbb{P}\left[\bigcup_{l\in S} H_l\right] \le \frac{p}{(1-\sqrt{p})^2}$$

which implies (via Lemma 4.1 in [Gács&Gál 1994]),

Fact 5

$$\mathbb{P}\left[\bigcup_{l\in S} H_l\right] \ge \left(1 - \frac{p}{(1-\sqrt{p})^2}\right) \sum_{l\in S} \mathbb{P}\left[H_l\right]$$

Error analysis Bounds on the total number of sensitive wires Fact 6

$$\mathbb{P}[H_l] = (1-\delta)^{|\beta_l|} \delta^{m_l - |\beta_l|} \ge \delta^{m_l}$$

Fact 4 & 5 \Rightarrow

$$\frac{p}{1 - 2\sqrt{p}} \ge \sum_{l \in S} \delta^{m_l}$$
$$\ge s \left(\prod_{l \in S} \delta^{m_l}\right)^{1/s}$$

which leads to

$$\sum_{l \in S} m_l \geq \frac{s}{\log(1/\delta)} \log\left(s \frac{1 - 2\sqrt{p}}{p}\right)$$

lower bound on the total number of "sensitive wires"

Lower bound on number of gates

Let N_C be the total number of gates in C:

$$n(\Phi_C)N_C \ge \sum_g n_g$$
$$\ge \sum_{l \in S} m_l$$
$$\ge \frac{s}{\log(1/\delta)} \log\left(s\frac{1-2\sqrt{p}}{p}\right)$$

Comments:

- The above proof is for $p \in (0, 1/4)$
- The case $p \in (1/4, 1/2)$ can be shown similarly.

Block Sensitivity

Let \mathbf{x}^{S} be a binary vector that differs from \mathbf{x} in the S subset of indicies, i.e.,

$$\mathbf{x}_i^S = \begin{cases} x_i & i \notin S \\ \neg x_i & i \in S \end{cases}$$

• *f* is (block) sensitive to *S* on \mathbf{x} if $f(\mathbf{x}^S) \neq f(\mathbf{x})$.

Block sensitivity of f on x: the largest number b such that

- there exists b disjoint sets S_1, S_2, \cdots, S_b
- for all $1 \le i \le b$, f is sensitive to S_i on \mathbf{x}
- Block sensitivity of f: maximum over all \mathbf{x} .
 - block sensitivity ≥ sensitivity

Theorem based on block sensitivity

- Let ε and p be any constants such that $\varepsilon \in (0, 1/2), p \in (0, 1/2)$.
- ▶ Let *f* be any Boolean function with block sensitivity *b*.

Under the error model (ε, p) , the number of gates of the curcuit is $\Omega(b \log b)$.

Discussions Lower bound for specific functions

Given an explicit function f of n variables, is there a lower boudn that is stronger than $\Omega(n \log n)$?

Open problem for

- unrestricted circuit C with complete basis
- function f that have $\Omega(n \log n)$ noiseless complexity for circuit C with some incomplete basis Φ

Discussions

Computation model

Exponential blowup

A noisy circuit with multiple levels

- The output of gates at level l goes to a gate at level l + 1
- Level 0 has n inputs
 - Level 0 has $N_0 = n \log n$ output gates
 - Level 1 has N₀ inputs
 - Level 1 has $N_1 = N_0 \log N_0$ output gates, ...

Why?

"The theorem is generally applicable only to the very first step of such a fault tolerant computation"

- If the input is not the original ones, we can choose them to make the sensitivity of a Boolean function to be 0.
 - $\blacktriangleright f(x_1, x_2, x_3, x_4, x_1 \oplus x_2 \oplus x_4, x_1 \oplus x_3 \oplus x_4, x_2 \oplus x_3 \oplus x_4)$
 - Lower bound does not apply: sensitivity is 0. How about block sensitivity?
- Problem formulation issue on the lower bound for coded input
 - coding is also computation!

Part II

Upper Bounds for the Complexity of Reliable Boolean Circuits with Noisy Gates

[Pippenger, "On Networks of Noisy Gates", 1985]

Overview

Achievability schemes in reliable computation with a network of nosiy gates.

- 1. System modeling
 - various types of computations
- 2. Change of basis and error levels
 - will skip
- 3. Functions with logarithmic redundancy
 - with explicit construction
 - for specific system parameters only
- 4. Functions with bounded redundancy
 - Presents a class of functions with "bounded redundancy"
 - Construction for reliable computation

System model: a revisit Weak vs. strong computation

perturbation and approximation

Let $f, g: \{0, 1\}^k \Rightarrow \{0, 1\},\$

- g is a ε -perturbation of f if $\mathbb{P}[g(\mathbf{x}) = f(\mathbf{x})] = 1 \varepsilon$ for any $\mathbf{x} \in \{0, 1\}^k$
- g is a ε -approximation of f if $\mathbb{P}[g(\mathbf{x}) = f(\mathbf{x})] \ge 1 \varepsilon$ for any $\mathbf{x} \in \{0, 1\}^k$

weakly (ε, δ) -computes

- gates: ε-perturbation
- output: δ -approximation

Why bother?

 \bullet *c*-perturbation may be helpful in randomized algorithms.

strongly (ε, δ) -computes

- gates: ε-approximation
- output: δ -approximation

Functions with logarithmic redundancy Main theorem

Theorem 3.1

If a Boolean function is computed by a noiseless network of size c, then it is also computed by a noisy network of size $O(c \log c)$.

Comments

- Provides explicit construction for some ε and δ values.
 - $\blacktriangleright \ \varepsilon = 1/512$
 - $\blacktriangleright \ \delta = 1/128$

Functions with logarithmic redundancy Construction

Strategy

Given a noiseless network with 2-input gates, construct a corresponding noisy network with 3-input gates.

Transformations

noiseless		noisy
each wire	\rightarrow	cable of m wires
gate	\rightarrow	module of $O(m)$
		noisy gates

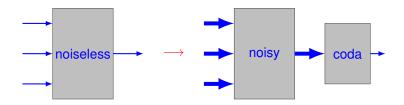
Additions

- coda: computes the majority of m wires with at most some error probability
 - ► Corollary 2.6: exists coda with size O (c log c)

• Choose $m = O(\log c)$

a cable is correct if at least $(1 - \theta)m$ component wires are correct

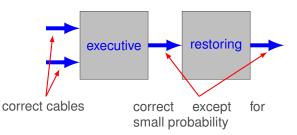
Overview



Module requirement

If the input cables are "correct", then the output cable will be correct except for some small error probability.

Module construction



Executive organ

 Construction: *m* noisy gates that compute the same function as the corresponding gate in noiseless network

Restoring organ

- Construction: a (m, k, α, β)-compressor
 - if at most αm inputs are incorrect, then at most βm outputs will be incorrect.

k = 8¹⁷,
$$\alpha = 1/64$$
, $\beta = 1/512$

Then

Choose system parameters properly, such that the resulting circuit has logarithmic redundancy. Functions with bounded redundancy Main results

Functions with bounded redundancy

For $r \ge 1$, let $s = 2^r$. Let

$$g_r(x_0, \dots, x_{r-1}, y_0, \dots, y_{s-1}) = y_t$$

where $t = \sum_{i=0}^{r-1} 2^i x_i$ i.e., t has binary representation $x_{r-1} \cdots x_1 x_0$.

Theorem 4.1

For every r and $s = 2^r$, g_r can be computed by a network of O(s) nosigigates.

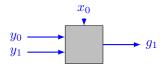
Comments

- \blacksquare g_r : "indicator function"
- Any noiseless networks that computes g_r has $\Omega(2^r)$ gates.
 - bounded redundancy
- Proof
 - Construct a network that strongly ($\varepsilon = 1/192, \delta = 1/24$)-computes g_r .

Construction

 g_1

$$g_1(x_0, y_0, y_1) = \begin{cases} y_0 & x_0 = 0\\ y_1 & x_1 = 1 \end{cases}$$



 g_r

$$g_2(x_0, x_1, y_0, y_1, y_2, y_3) = \begin{cases} y_0 & x_1 x_0 = 00\\ y_1 & x_1 x_0 = 01\\ y_2 & x_1 x_0 = 10\\ y_3 & x_1 x_0 = 11 \end{cases}$$

. . .

 \blacksquare g_r can be implemented by a binary tree with $2^r - 1$ elements of g_1 .

- ▶ level r 2: root
- level 0: leaves
- y_t : corresponds to a path from level 0 to r-2

Construction (cont.)

- Each path only contains one gate at each level
- If each gate at level $k, 0 \le k \le r 2$ fails with probability $\Theta((a\varepsilon)^k)$, then the failure probability for a path is $\Theta(\varepsilon)$.

Construction: replace wires by cables, gates by modules

cable at level k

- input: 2k 1 wires
- output: 2k + 1 wires
- module at level k
 - ▶ 2k+1 disjoint networks
 - each compute the (2k-1)-argument majority of the input wires
 - ▶ then apply g₁
 - ▶ noiseless complexity: $O(k) \Rightarrow$ noisy complexity: $O(k \log k)$
 - $\blacksquare O(k^2 \log k)$ noisy gates at level k
 - error probability for each nosiy network: 2ε

error probability for module: $4\varepsilon(8\varepsilon)^k = \Theta\left((8\varepsilon)^k\right)$

- use coda at the root output for majority vote
- total #gate: $O(s) = O(2^r)$

Networks with more than one input

A network with outputs w_1, w_2, \ldots, w_m strongly (ε, δ) -computes f_1, f_2, \ldots, f_m if, for every $1 \leq j \leq m$, the network obtained by ignoring all but the output w_j strongly (ε, δ) -computes f_j .

Theorem 4.2

For every $a \ge 1$ and $b = 2^{2^a}$, let $h_{a,0}(z_0, \dots, z_{a-1}), \dots, h_{a,b-1}(z_0, \dots, z_{a-1})$ denote the *b* Boolean functions of *a* Boolean argument.

Then $h_{a,0}(z_0, \dots, z_{a-1}), \dots, h_{a,b-1}(z_0, \dots, z_{a-1})$ can be strongly computed by a network of O(b) noisy gates.

Proof: similar to Theorem 4.1

Boolean function with n Boolean arguments

Theorem 4.3

Any Boolean function of n Boolean arguments can be computed by a network of $O\left(2^n/n\right)$ noisy gates.

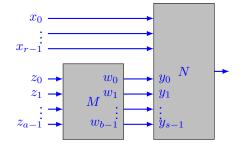
Proof

• Let
$$a = \lfloor \log_2(n - \log_2 n) \rfloor$$
,
 $b = 2^{2^a} = 2^n/n, r = n - a$ and
 $s = 2^r = 2^n/n$.

- Theorem 4.2: M strongly computes $h_{a,0}(z_0, \cdots, z_{a-1})$, \cdots , $h_{a,b-1}(z_0, \cdots, z_{a-1})$
 - ► $O(b) = O(2^n/n)$ gates
- Theorem 4.1: N strongly computes

$$g_r(x_0, \ldots, x_{r-1}, y_0, \ldots, y_{s-1})$$

• $O(s) = O(2^n/n)$ gates



M and *N*: strongly computes any Boolean function with *n* Boolean arguments $x_0, x_1, \dots, x_{r-1}, z_0, z_1, \dots, z_{a-1}$.

Bounded redundancy for Boolean functions

Implication of Theorem 4.3

- [Muller, "Complexity in Electronic Switching Circuits", 1956]: "Almost all" Boolean functions of n Boolean arguments are computed only by noiseless networks with Ω (2ⁿ/n) gates
- "Almost all" Boolean functions have bounded redundancy.

Set of Boolean linear functions

- A set of *m* Boolean functions $f_1(x_1, \dots, x_n), \dots, f_m(x_1, \dots, x_n)$ is linear if each of the functions is the sum (modulo 2) of some subset of the *n* Boolean arguments x_1, \dots, x_n .
- "Almost all" sets of n linear functions of n Boolean arguments have bounded redundancy.
 - Similar approach
 - Theorem 4.4

Further readings...

- N. Pippenger, "Reliable computation by formulas in the presence of noise", 1988
- T. Feder, "Reliable computation by networks in the presence of noise", 1989